IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Rajski et al.
Application No. 09/620,021
Filed: July 20, 2000
Confirmation No. 3823
For: CONTINUOUS APPLICATION AND DECOMPRESSION OF TEST PATTERNS TO A CIRCUIT-UNDER-TEST
Examiner: Phung M. Chung
Art Unit: 2133
Attorney Reference No. 1011-54375-01

CERTIFICATE OF MAILING

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Listed on the accompanying form PTO-1449 and enclosed herewith are several English-language documents. Applicants respectfully request that these documents be listed as references cited on the issued patent. This Information Disclosure Statement ("IDS") is being mailed before Applicants received a final action, a notice of allowance, or an action that otherwise closes prosecution in the referenced application.

Copies of United States patents and United States published patent applications do not have to be provided to the Patent Office (37 C.F.R. 1.98(a)(2)(ii)). Copies of unpublished U.S. applications do not have to be provided, as long as the application is available on PAIR, as this requirement of 37 C.F.R. § 1.98(a)(2)(iii) has been waived by the United States Patent and Trademark Office pursuant to the Official Gazette Notice on October 19, 2004 (1287 OG 163). Applicants will provide copies of such patents or applications upon request.

Submitted herewith is a check for $180.00 as required by 37 C.F.R. § 1.17(p) for filing this IDS in compliance with 1.97(c).

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The filing of this IDS shall not be construed to be an admission that the information cited in the statement is, or is considered to be, prior art or otherwise material to patentability as defined in 37 C.F.R. §1.56.

Respectfully submitted,

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Filing Date	July 20, 2000
First Named Inventor	Rajski
Art Unit	2133
Examiner Name	Phung M. Chung

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

U.S. PATENT DOCUMENTS

Copies of U.S. Patent documents do not need to be provided, unless requested by the Patent and Trademark Office. For patents, provide the patent number and the issue date. For published U.S. applications, provide the publication number and the publication date. For unpublished pending patent applications, provide the application number and the filing date.

Examiner's Initials*	Cite No. (optional)	Number	Publication Date	Name of Applicant or Patentee
		6,272,653	8.27.2001	Amstutz
		6,308,291	10.23.2001	Kock et al.

FOREIGN PATENT DOCUMENTS

Examiner's Initials*	Cite No. (optional)	Country	Number	Publication Date	Name of Applicant or Patentee

Examiner's Initials*	Cite No. (optional)	OTHER DOCUMENTS
		Aitken et al., "A Diagnosis Method Using Pseudo-Random Vectors Without Intermediate Signatures," *Proc. ICCAD*, pp. 574-577 (1989).
		Bardell et al., Built-In Test for VLSI Pseudorandom Techniques, Chapter 4, "Test Response Compression Techniques," John Wiley & Sons, Inc., pp. 89-108 (1987).
		Benowitz et al., "An Advanced Fault Isolation System for Digital Logic," *IEEE Transactions on Computers*, Vol. C-24, No. 5, pp. 489-497 (May 1975).
		Chakrabarty et al., "Optimal Zero-Aliasing Space Compaction of Test Responses," *IEEE Transactions on Computers*, Vol. 47, No. 11, pp. 1171-1187 (November 1998).
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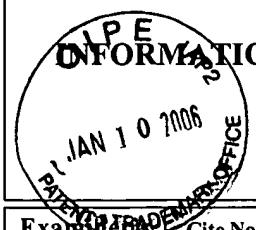
EXAMINER SIGNATURE:	DATE CONSIDERED:

* Examiner: Initial if reference considered, whether or not in conformance with MPEP 609. Draw line through cite if not in conformance and not considered. Include copy of this form with next communication to applicant.



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		Ghosh-Dastidar et al., "Fault Diagnosis in Scan-Based BIST Using Both Time and Space Information," *Proc. ITC*, pp. 95-102 (September 1999).
		Karpovsky et al., "Board-Level Diagnosis by Signature Analysis," *Proc. ITC*, pp. 47-53 (1988).
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		Saluja et al., "Testing Computer Hardware through Data Compression in Space and Time," *Proc. ITC*, pp. 83-88 (1983).
		Wu et al., "Scan-Based BIST Fault Diagnosis," *IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems*, Vol. 18, No. 2, pp. 203-211 (February 1999).

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